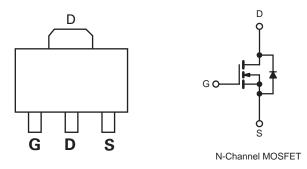


SGM0410S-VB Datasheet

N-Channel 100 V (D-S) MOSFET

MOSFET PRODUCT SUMMARY							
V _{DS} (V)	R _{DS(on)} (Ω) Typ.	I _D (A) ^a	Q _g (Typ.)				
100	0.102 at V _{GS} = 10 V	4.2					
	0.120 at V _{GS} = 6 V	3.8	2.9 nC				
	0.125 at V _{GS} = 4.5 V	3.6					



FEATURES

- Trench Power MOSFET
 100 % R_g and UIS Tested



COMPLIANT HALOGEN

APPLICATIONS

- DC/DC Converters / Boost Converters
- Load Switch
- LED Backlighting in LCD TVs
- · Power Management for Mobile Computing

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	100	V
Gate-Source Voltage	V _{GS}	± 20		
	T _C = 25 °C		4.2	
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C	1-	3.5	
Continuous Drain Current (1j = 130°C)	T _A = 25 °C	I _D	3.2 ^{b,c}	
	T _A = 70 °C		2.8 ^{b,c}	٨
Pulsed Drain Current (t = 300 µs)	I _{DM}	15	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	la la	2.1	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	1 ^{b, c}	
Single Pulse Avalanche Current	1 0.1 mll	I _{AS}	3	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	0.45	mJ
	T _C = 25 °C		2.5	
Maximum Power Dissipation	T _C = 70 °C	PD	1.6	w
	T _A = 25 °C		1.25 ^{b, c}	v
	T _A = 70 °C		0.8 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS								
Parameter	Symbol	Typical	Maximum	Unit				
Maximum Junction-to-Ambient ^{b, d}	≤ 5 s	R _{thJA}	75	100	°C/W			
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	40	50	0/11			

Notes:

a. Based on $T_C = 25$ °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166 °C/W.

MOSFET SPECIFICATIONS	(T _J = 25 °C	, unless otherwise noted)				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	100			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		59		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	_		- 4.8		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.2		3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V$, $V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μA
Zelo Gale voltage Diam Guirent	'DSS	V_{DS} = 100 V, V_{GS} = 0 V, T_{J} = 55 °C			- 10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, V_{GS} = 10 V	5			Α
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 2 \text{ A}$		0.102		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 6 V, I _D = 1 A		0.120		
		V _{GS} = 4.5 V, I _D = 1 A		0.125		
Forward Transconductance ^a	g _{fs}	V _{DS} = 20 V, I _D = 2 A		5		S
Dynamic ^b		-	I			
Input Capacitance	C _{iss}			196		r – – –
Output Capacitance	C _{oss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		67		pF
Reverse Transfer Capacitance	C _{rss}			14		
		V _{DS} = 50 V, V _{GS} = 10 V, I _D = 2.2 A		5.2	10.4	-
Total Gate Charge	Qg			2.9	5.8	
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 2.2 \text{ A}$		1	0.0	nC
Gate-Drain Charge	Q _{gd}			1.4		-
Gate Resistance	R _q	f = 1 MHz	0.9	4.3	8.6	Ω
Turn-On Delay Time	t _{d(on)}			40	60	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{1} = 27.7 \Omega$		68	102	-
Turn-Off Delay Time	t _{d(off)}	$I_{\rm D} = 1.8$ A, $V_{\rm GEN} = 4.5$ V, $R_{\rm g} = 1 \Omega$		14	21	
Fall Time	t _f	5 52.1 9		20	30	
Turn-On Delay Time	t _{d(on)}			8	16	ns
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_1 = 27.7 \Omega$		10	20	
Turn-Off Delay Time	t _{d(off)}	$I_{\rm D} = 1.8$ A, $V_{\rm GEN} = 10$ V, $R_{\rm g} = 1 \Omega$		10	20	
Fall Time	t _f			7	14	-
Drain-Source Body Diode Characterist				<u> </u>		
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	Ι		- 2.1	[
Pulse Diode Forward Current ^a	I _{SM}	0		1	- 8	A
Body Diode Voltage	V _{SD}	I _S = 1.8 A		- 0.8	- 1.2	V
Body Diode Voltage Body Diode Reverse Recovery Time	vsD t _{rr}			23	35	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 1.8 A, dl/dt = 100 A/μs,		23	32	nC
		$T_F = 1.8 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$ $T_{.1} = 25 \text{ °C}$			32	
Reverse Recovery Fall Time	t _a	20 0		17		ns
Reverse Recovery Rise Time	t _b			6		

Notes:

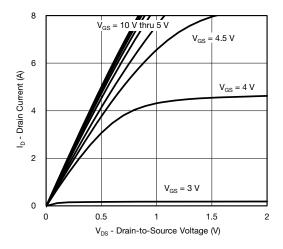
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

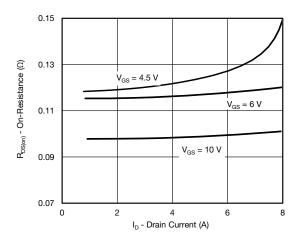
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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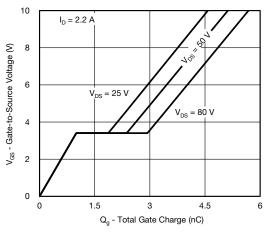




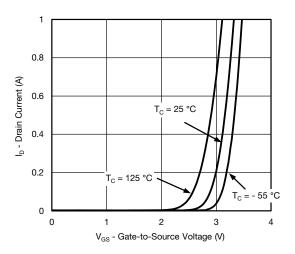




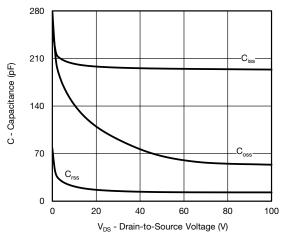
On-Resistance vs. Drain Current and Gate Voltage



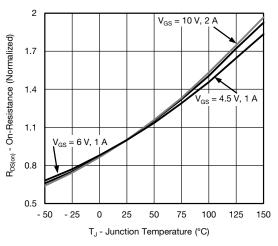
Gate Charge



Transfer Characteristics

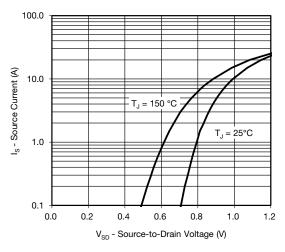




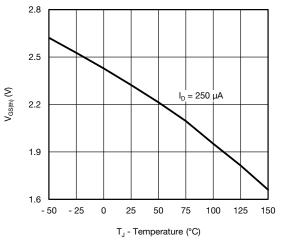


On-Resistance vs. Junction Temperature

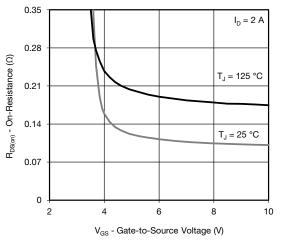




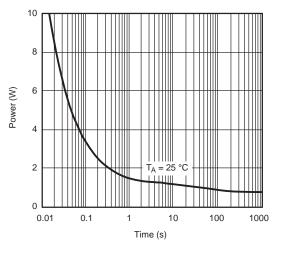
Source-Drain Diode Forward Voltage



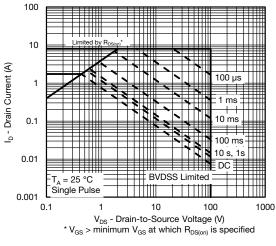




On-Resistance vs. Gate-to-Source Voltage

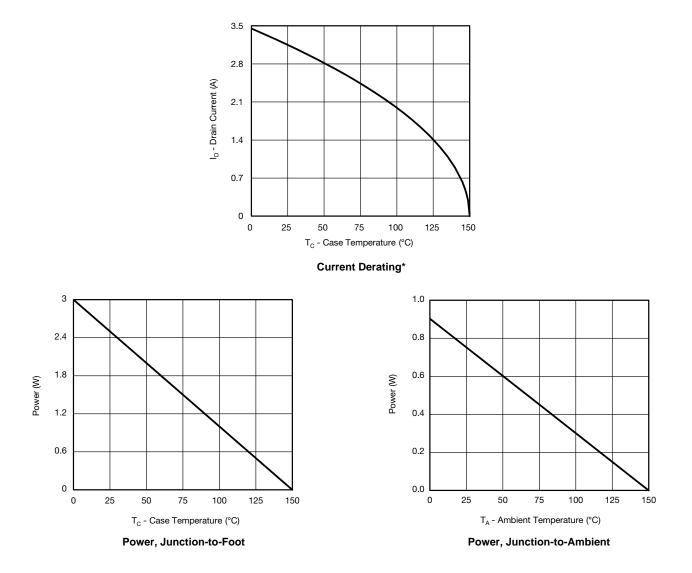






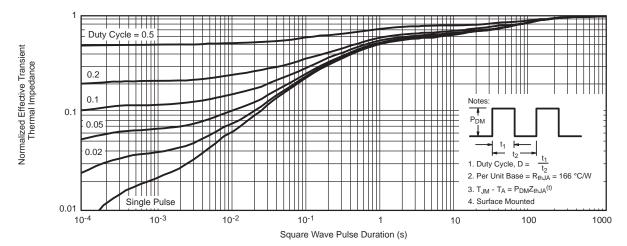
Safe Operating Area





* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





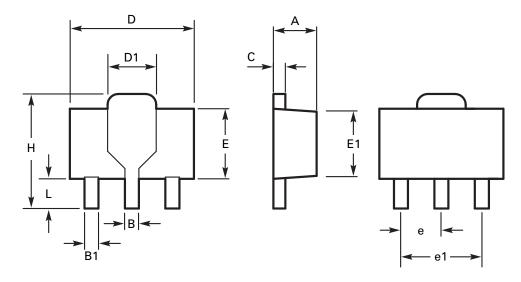
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



Package outline - SOT89



DIM	Millimeters		Inches		DIM	Millimeters		Inches	
	Min	Max	Min	Max		Min	Max	Min	Max
А	1.40	1.60	0.550	0.630	E	2.29	2.60	0.090	0.102
В	0.44	0.56	0.017	0.022	E1	2.13	2.29	0.084	0.090
B1	0.36	0.48	0.014	0.019	е	1.50 BSC		0.059 BSC	
С	0.35	0.44	0.014	0.017	e1	3.00 BSC		0.118	BSC
D	4.40	4.60	0.173	0.181	Н	3.94	4.25	0.155	0.167
D1	1.62	1.83	0.064	0.072	L	0.89	1.20	0.035	0.047

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches



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